

Notice of References Cited

Application/Control No.

10/594,065

Applicant(s)/Patent Under
Reexamination
TAKEUCHI ET AL.

Examiner

VERNON P. WEBB

Art Unit

2811

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0160253 A1	08-2003	Udagawa, Takashi	257/85
*	B	US-2006/0094140 A1	05-2006	Inoguchi et al.	438/022
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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